Search Notes



Application/Control No.

Applicant(s)/Patent Under Reexamination

ATIAS ET AL.

Examiner

Trujillo, James K

Art Unit

2116

SEARCHED

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Class	Subclass	Date Examin						

SEARCH NOTES

Search Notes	Date	Examiner
EAST (USPAT, US-PGPUB, EPO, JPO, DERWENT, IBM_TDB), see attached; NPL: IEEE; Inventor Search/DP	11/22/06	JKT
Updated - see attached	4/16/07	JKT

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